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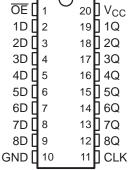
OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOP **WITH 3-STATE OUTPUTS**

FEATURES

- **Qualified for Automotive Applications**
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Operates From 2 V to 3.6 V
- Inputs Accept Voltages to 5.5 V
- Max t_{pd} of 7 ns at 3.3 V
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- **Supports Mixed-Mode Signal Operation on All** Ports (5-V Input/Output Voltage With 3.3-V V_{CC})
- I_{off} Supports Partial-Power-Down Mode Operation

(TOP VIEW) OE [] 1 1D 🛮 2 19**∏** 1Q 2D 🛮 3 18 2Q

DW OR PW PACKAGE



DESCRIPTION/ORDERING INFORMATION

The SN74LVC574A octal edge-triggered D-type flip-flop is designed for 2.7-V to 3.6-V V_{CC} operation.

This device features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels at the data (D) inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

This device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of this device as a translator in a mixed 3.3-V/5-V system environment.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION⁽¹⁾

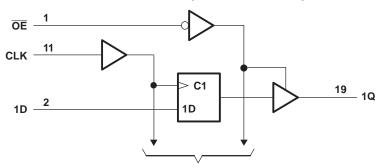
T _A	PACKAGE ⁽²⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 125°C	SOIC - DW	Reel of 2000	SN74LVC574AQDWRQ1	L574AQ1
-40 C to 125 C	TSSOP - PW	Reel of 2000	SN74LVC574AQPWRQ1	L574AQ1

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

FUNCTION TABLE (EACH FLIP-FLOP)

	INPUTS		OUTPUT
ŌĒ	CLK	D	Q
L	↑	Н	Н
L	↑	L	L
L	L	X	Q_0
Н	X	X	Z

LOGIC DIAGRAM (POSITIVE LOGIC)



To Seven Other Channels

Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		-0.5	6.5	V
V _I	Input voltage range ⁽²⁾		-0.5	6.5	V
Vo	Voltage range applied to any output in the high-in	mpedance or power-off state (2)	-0.5	6.5	V
Vo	Voltage range applied to any output in the high of	or low state (2)(3)	-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		– 50	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V _{CC} or GND			±100	mA
0	DW package			58	°C/W
θ_{JA}	Package thermal impedance (4)	PW package		83	C/VV
T _{stg}	Storage temperature range		-65	150	°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- 3) The value of V_{CC} is provided in the recommended operating conditions table.
- (4) The package thermal impedance is calculated in accordance with JESD 51-7.

Submit Documentation Feedback



Recommended Operating Conditions⁽¹⁾

			MIN	MAX	UNIT
.,	Complexed	Operating	2	3.6	V
V _{CC}	Supply voltage	Data retention only	1.5		V
V _{IH}	High-level input voltage	V _{CC} = 2.7 V to 3.6 V	2		V
V _{IL}	Low-level input voltage	V _{CC} = 2.7 V to 3.6 V		0.8	V
VI	Input voltage	•	0	5.5	V
	Outrout valte as	High or low state	0	V_{CC}	V
v _O	V _O Output voltage	3-state	0	5.5	V
	High level evitevit evinent	V _{CC} = 2.7 V		-12	A
I _{OH}	High-level output current	V _{CC} = 3 V		-24	mA
	Law l	V _{CC} = 2.7 V		12	1
I _{OL}	I _{OL} Low-level output current	V _{CC} = 3 V		24	mA
Δt/Δν	Input transition rise or fall rate	Ţ		6	ns/V
T _A	Operating free-air temperature		-40	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	V _{CC}	MIN	TYP ⁽¹⁾ MAX	UNIT
	$I_{OH} = -100 \mu A$		2.7 V to 3.6 V	V _{CC} - 0.2		
V	1 10 m A		2.7 V	2.2		V
V_{OH}	$I_{OH} = -12 \text{ mA}$		3 V	2.4		V
	I _{OH} = -24 mA		3 V	2.2		
	I _{OL} = 100 μA		2.7 V to 3.6 V		0.2	
V_{OL}	I _{OL} = 12 mA		2.7 V		0.4	V
	I _{OL} = 24 mA		3 V		0.55	
I _I	V _I = 0 to 5.5 V		3.6 V		±5	μΑ
I _{OZ}	V _O = 0 to 5.5 V		3.6 V		±15	μΑ
	$V_I = V_{CC}$ or GND	1 - 0	3.6 V		10	
I _{CC}	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{(2)}$	$I_{O} = 0$	3.0 V		10	μΑ
ΔI _{CC}	One input at V _{CC} - 0.6 V,	Other inputs at V _{CC} or GND	2.7 V to 3.6 V		500	μΑ
C _i	$V_I = V_{CC}$ or GND		3.3 V		4	pF
C _o	$V_O = V_{CC}$ or GND		3.3 V		5.5	pF

⁽¹⁾ All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		150		150	MHz
t _w	Pulse duration, CLK high or low	3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	2		2		ns
t _h	Hold time, data after CLK↑	2		2		ns

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⁽²⁾ This applies in the disabled state only.



Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	V _{CC} =	2.7 V	V _{CC} = 0.3	3.3 V 3 V	UNIT
	(INPUT)	(001701)	MIN	MAX	MIN	MAX	
f _{max}			150		150		MHz
t _{pd}	CLK	Q		8	1	7	ns
t _{en}	ŌĒ	Q		9	1	7.5	ns
t _{dis}	ŌĒ	Q		7	0.5	6.4	ns

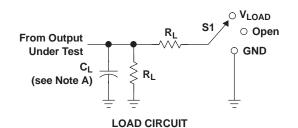
Operating Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER		TEST CONDITIONS	V _{CC} = 2.5 V TYP	V _{CC} = 3.3 V TYP	UNIT
0	Dower discination conscitance per flip flor	Outputs enabled	f = 10 MHz	60	43	pF
C _{pd}	Power dissipation capacitance per flip-flop	Outputs disabled	I = IO MINZ	9	15	þΓ

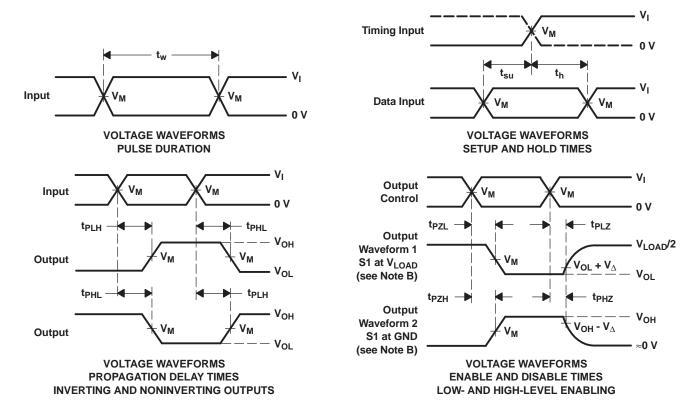


PARAMETER MEASUREMENT INFORMATION



TEST	S1
t _{PLH} /t _{PHL} t _{PLZ} /t _{PZL} t _{PHZ} /t _{PZH}	Open V _{LOAD} GND

.,	INF	PUTS	.,	V			.,
V _{CC}	VI	t _r /t _f	V _M	V_{LOAD}	C _L	R _L	V_Δ
2.7 V	2.7 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
3.3 V \pm 0.3 V	2.7 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_{O}=50~\Omega$.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
CLVC574AQDWRG4Q1	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1
CLVC574AQDWRG4Q1.B	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1
CLVC574AQPWRG4Q1	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1
CLVC574AQPWRG4Q1.B	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1
SN74LVC574AQDWRQ1	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1
SN74LVC574AQDWRQ1.B	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L574AQ1

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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OTHER QUALIFIED VERSIONS OF SN74LVC574A-Q1:

◆ Catalog : SN74LVC574A

● Enhanced Product : SN74LVC574A-EP

Military : SN54LVC574A

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

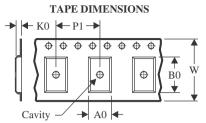
• Military - QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

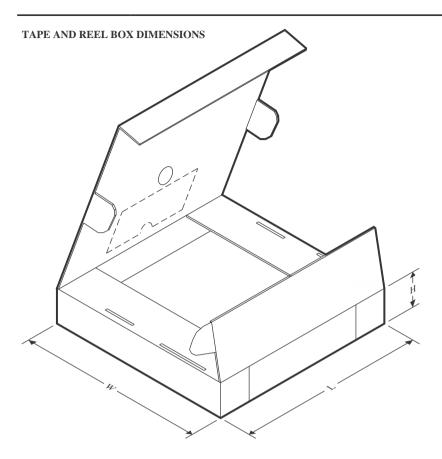
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CLVC574AQDWRG4Q1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CLVC574AQPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74LVC574AQDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

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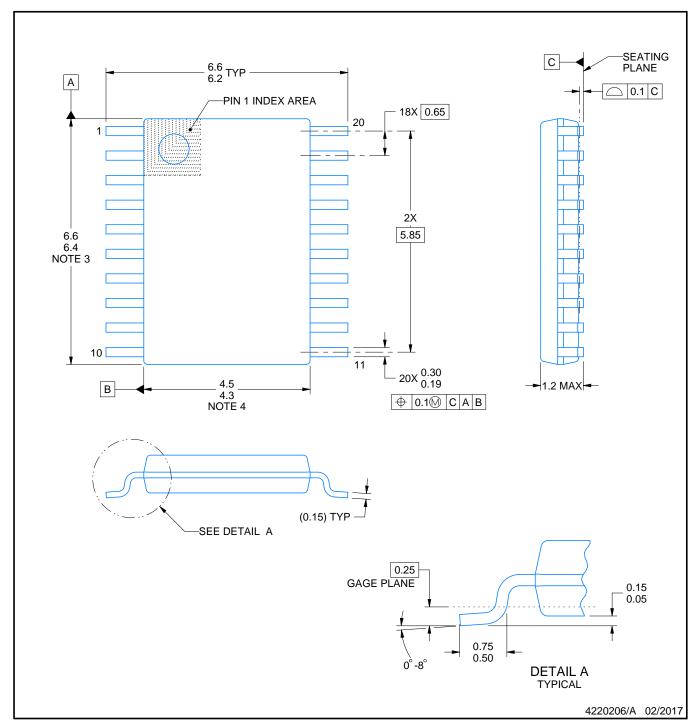


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CLVC574AQDWRG4Q1	SOIC	DW	20	2000	356.0	356.0	45.0
CLVC574AQPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0
SN74LVC574AQDWRQ1	SOIC	DW	20	2000	356.0	356.0	45.0



SMALL OUTLINE PACKAGE



NOTES:

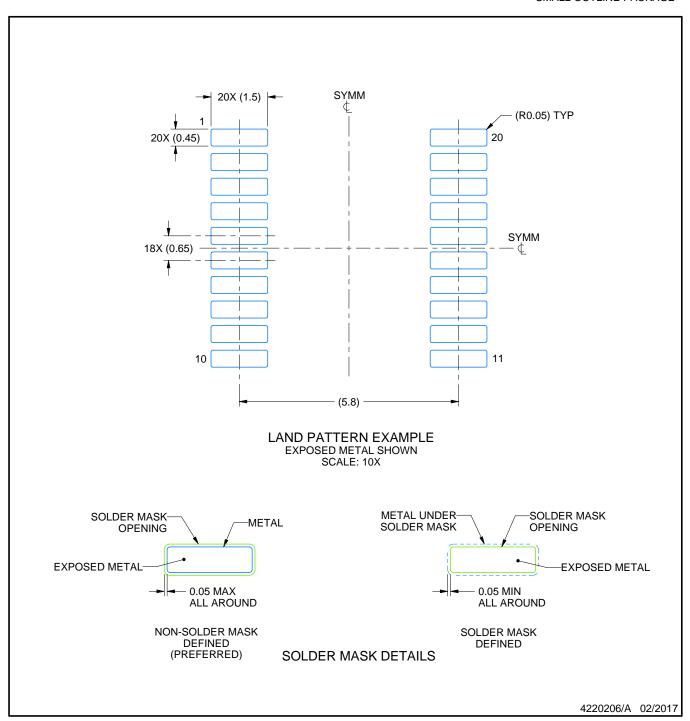
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



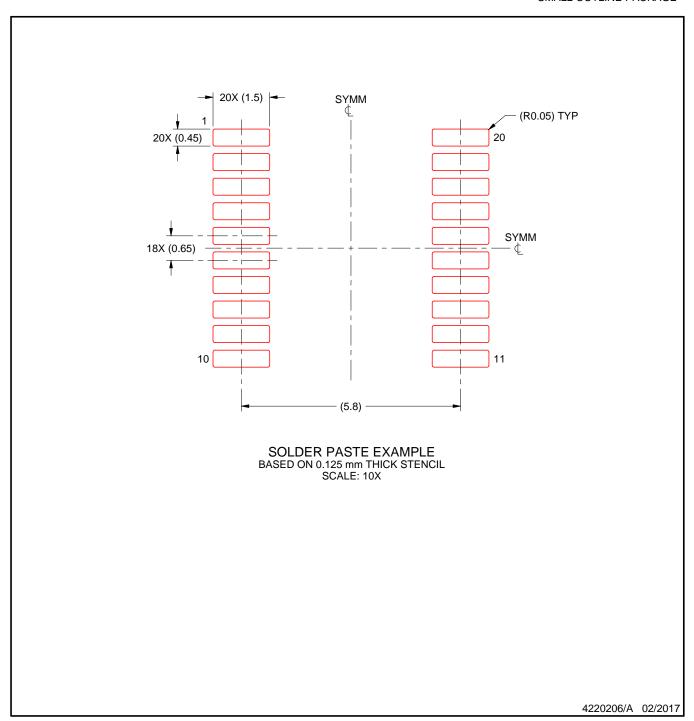
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



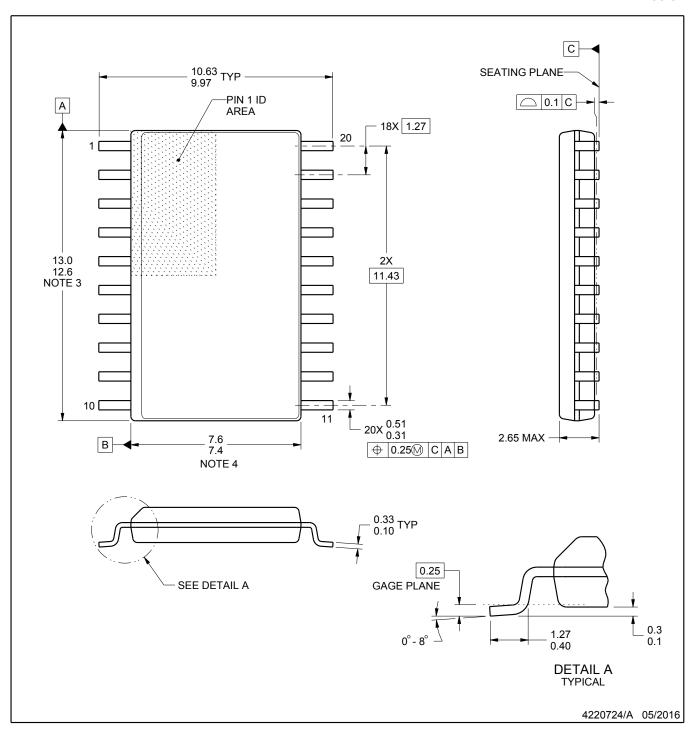
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



NOTES:

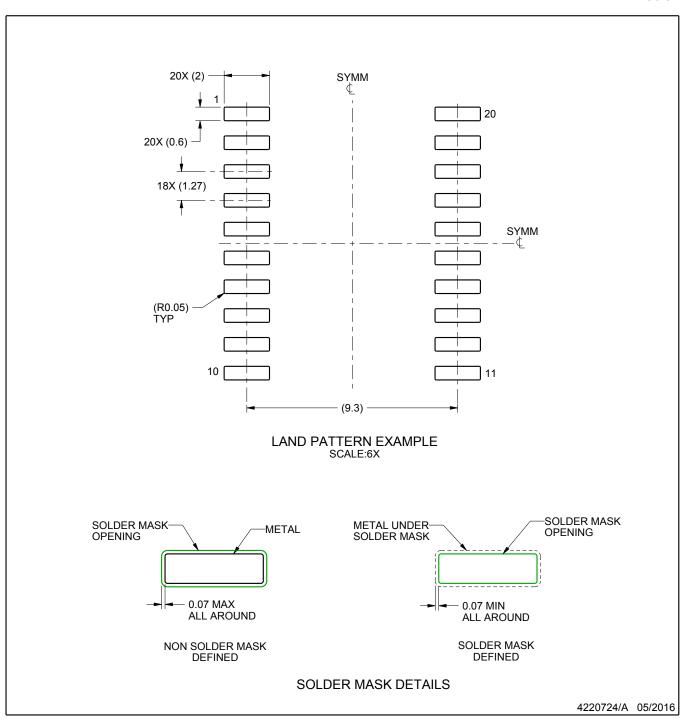
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 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



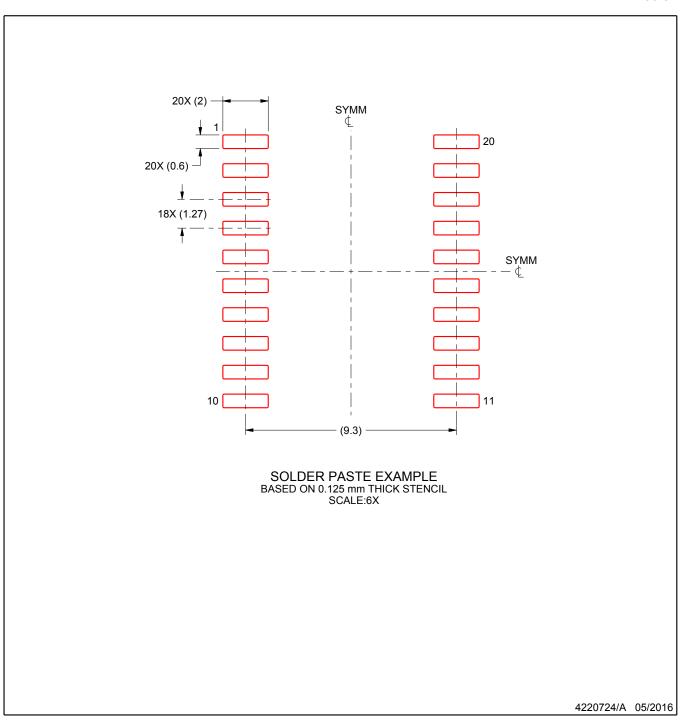
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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